



OCT 17 2003

Patent No. 241749US2/phh

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Yukio TANIGUCHI

SERIAL NO: 10/661,600

GAU:

FILED: September 15, 2003

EXAMINER:

FOR: CRYSTALLIZATION APPARATUS, CRYSTALLIZATION METHOD, AND PHASE SHIFT MASK AND FILTER FOR USE IN THESE APPARATUS AND METHOD

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yukio TANIGUCHI

SERIAL NO: 10/661,600

GROUP:

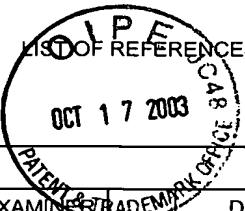
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METHOD

STATEMENT OF RELEVANCY

Reference AW on Form 1449 is discussed in the specification.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242749US2		SERIAL NO. 10/661,600	
 LIST OF REFERENCES CITED BY APPLICANT OCT 17 2003 C-8		APPLICANT Yukio TANIGUCHI					
		FILING DATE September 15, 2003				GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
AA							
AB							
AC							
AD							
AE							
AF							
AG							
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AJ							
AK							
AL							
AM							
AN							
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION		
					YES	NO	
AO	1 047 119	10/25/2000	EUROPE				
AP							
AQ							
AR							
AS							
AT							
AU							
AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	C.-H. OH, et al., Applied Surface Science 154-155, pages 105-111, "OPTIMIZATION OF PHASE-MODULATED EXCIMER-LASER ANNEALING METHOD FOR GROWING HIGHLY-PACKED LARGE-GRAINS IN Si THIN-FILMS ", 2000						
AX							
AY							
AZ				<input type="checkbox"/> Additional References sheet(s) attached			
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							